

LUP12N65 / LUF12N65

650V N-Channel Enhancement Mode MOSFET

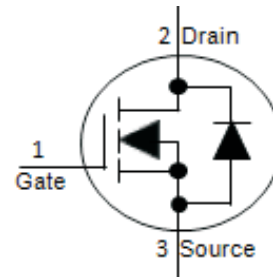
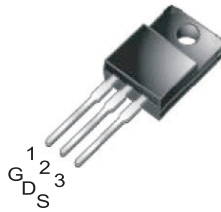
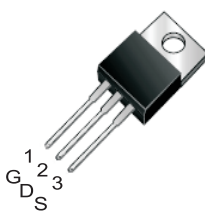
Product General Description

These enhancement mode power field effect transistors have been advanced technology design to provide low on-state resistance, high avalanche energy. These devices are well suited for popular AC-DC applications, active power factor correction, ballasts based on half-bridge topology.

Features

12A , 650V, $R_{DS(ON)}=0.8\Omega@V_{GS}=10V$, $I_D=6.0A$

- Low On-state Resistance
- Fast Switching
- Low Gate Charge
- Fully Characterized Avalanche Voltage and Current



Marking and Order Information

TYPE	MARKING	PACKAGE	PACKING
LUP12N65	P12N65	TO-220	50PCS/TUBE
LUF12N65	F12N65	TO-220F	50PCS/TUBE

Absolute Maximum Ratings and Thermal Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	ULP12N65	ULF12N65	Units
Drain-Source Voltage	V_{DS}	650		V
Gate-Source Voltage	V_{GS}	± 30		V
Continuous Drain Current	I_D	12	12	A
Pulsed Drain Current ¹⁾	I_{DM}	48	48	A
Avalanche Energy with Single Pulse $I_{AS}=12A$, $V_{DD}=90V$, $L=12mH$	E_{AS}	990		mJ
Maximum Power Dissipation Derating Factor	P_D	175 1.4	52 0.42	W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to +150		$^\circ\text{C}$
Junction-to-Case Thermal Resistance	$R_{\theta JC}$	0.7	2.4	$^\circ\text{C/W}$
Junction-to Ambient Thermal Resistance	$R_{\theta JA}$	62.5	100	$^\circ\text{C/W}$

Note : 1. Maximum DC current limited by the package

IMPROVE PRODUCT DESIGN,FUNCTIONS AND RELIABILITY WITHOUT NOTICE

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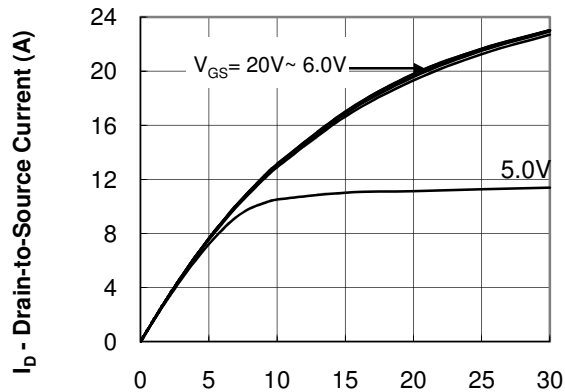
650V N-Channel Enhancement Mode MOSFET

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Units
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	650	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	-	4.0	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=6.0A$	-	0.66	0.8	Ω
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=650V, V_{GS}=0V$	-	-	10	μA
Gate Body Leakage	I_{GSS}	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	± 100	nA
Dynamic						
Total Gate Charge	Q_g	$V_{DS}=520V, I_D=12A,$ $V_{GS}=10V$	-	46.8	62	nC
Gate-Source Charge	Q_{gs}		-	9.2	-	
Gate-Drain Charge	Q_{gd}		-	14.6	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=325V, I_D=12A$ $V_{GS}=10V, R_G=25\Omega$	-	16.2	24	ns
Turn-On Rise Time	t_r		-	26.8	42	
Turn-Off Delay Time	$t_{d(off)}$		-	56	98	
Turn-Off Fall Time	t_f		-	24.6	38	
Input Capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V$ $f=1.0MHz$	-	1800	2450	pF
Output Capacitance	C_{oss}		-	145	195	
Reverse Transfer Capacitance	C_{rss}		-	16	22	
Source-Drain Diode						
Max. Diode Forward Current	I_S	-	-	-	12	A
Max.Pulsed Source Current	I_{SM}	-	-	-	48	A
Diode Forward Voltage	V_{SD}	$I_S=12A, V_{GS}=0V$	-	-	1.4	V
Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_F=12A$ $di/dt=100A/\mu s$	-	450	-	ns
Reverse Recovery Charge	Q_{rr}		-	5.0	-	μC

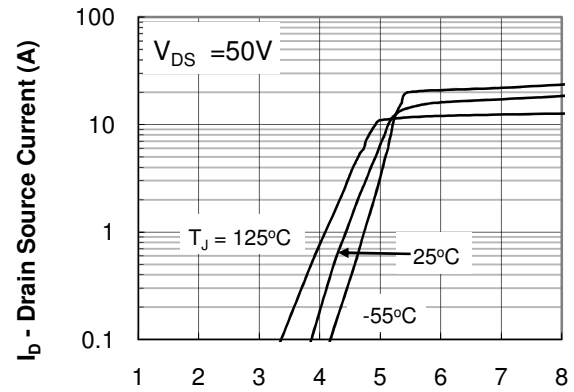
NOTE : Plus Test : Pluse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.

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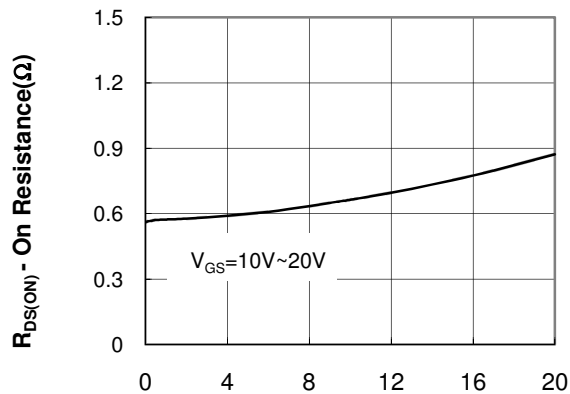
Typical Characteristics Curves ($T_c=25^\circ\text{C}$, unless otherwise noted)



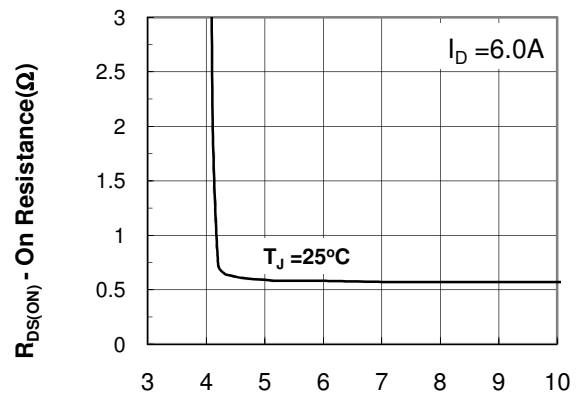
V_{DS} - Drain-to-Source Voltage (V)
Output Characteristic



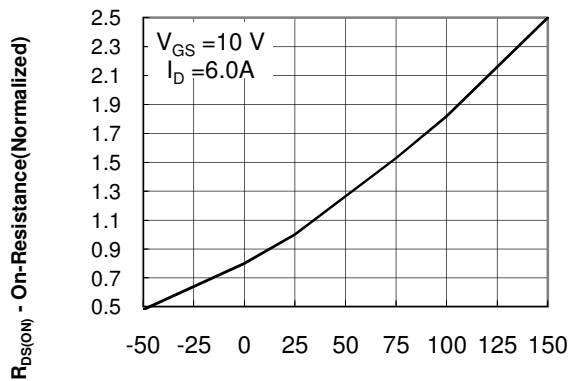
V_{GS} - Gate-to-Source Voltage (V)
Transfer Characteristic



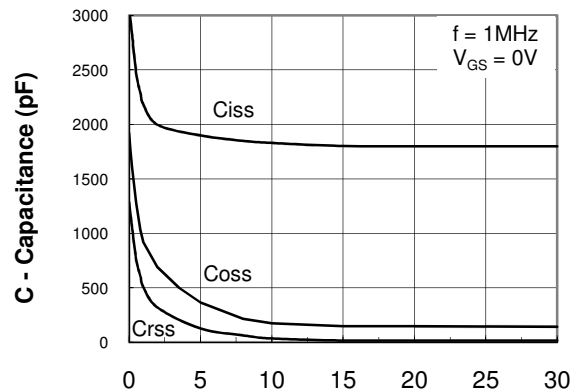
I_D - Drain Current (A)
On Resistance vs Drain Current



V_{GS} - Gate-to-Source Voltage (V)
On Resistance vs Gate to Source Voltage



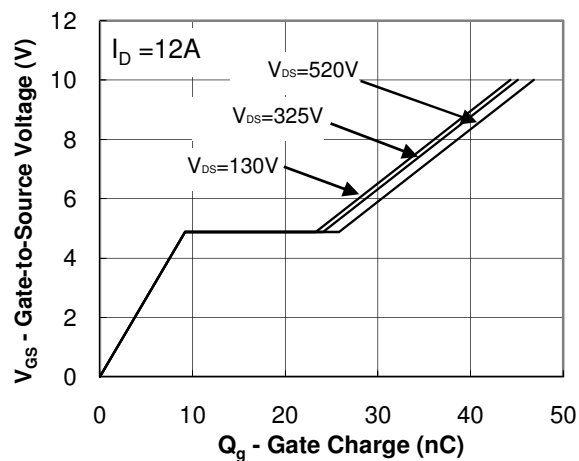
T_J - Junction Temperature ($^\circ\text{C}$)
On Resistance vs Junction Temperature



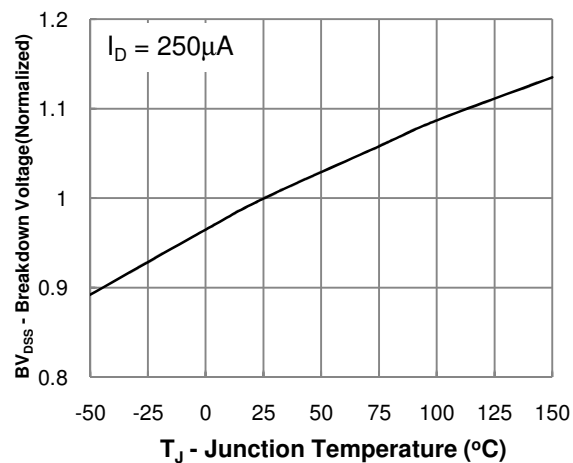
V_{DS} - Drain-to-Source Voltage (V)
Capacitance

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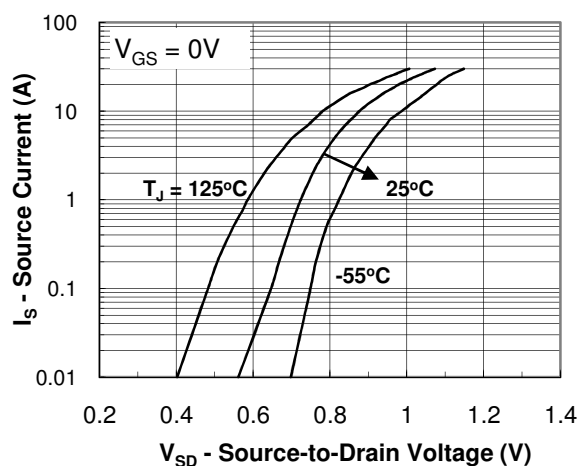
Typical Characteristics Curves ($T_C=25^\circ\text{C}$, unless otherwise noted)



Gate Charge Waveform



Breakdown Voltage vs Junction Temperature



Source-Drain Diode Forward Voltage